CONTROL STORE SEQUENCER

PRELIMINARY SPECIFICATION

8X02-I.XL

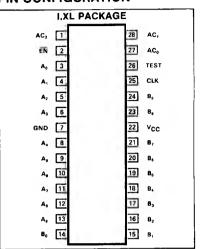
DESCRIPTION

The Signetics 8X02 is a low power Schottky LSI device intended for use in high performance microprogrammed systems to control the fetch sequence of microinstructions. When combined with standard ROM or PROM, the 8X02 forms a powerful microprogrammed control section for computers, controllers, or sequential logic.

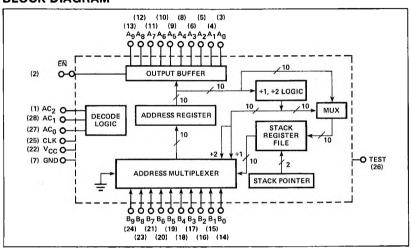
FEATURES

- Low power Schottky process
- 1024 microinstruction addressability
- N-way branch
- 4-level stack register file (LIFO type)
- Automatic push/pop stack operation
- "Test and skip" operation on test input line
- 3-bit command code
- Tri-state buffered outputs
- Auto-reset to address 0 during power-up
- Conditional branching, pop stack, and push stack

PIN CONFIGURATION



BLOCK DIAGRAM



PIN DESIGNATION

PIN SYMBOL		NAME AND FUNCTION	TYPE	
5-6 8-13	A ₀ -A ₉	Microprogram Address outputs	Three-state Active high	
1,28,27	AC ₀ -AC ₂	Next Address Control Function inputs All addressing control functions are selected by these command lines.	Active high	
14-21 23-24	B ₀ -B ₉	Branch Address inputs Determines the next address of an N-way branch when used with the BRANCH TO SUBROUTINE (BSR) or BRANCH ON TEST (BRT) command.	Active high	
2	EN	Enable input When in the low state, the Microprogram Address outputs are enabled.	Active low	
25	CLK	Clock Input—High to Low transition for stack operations, Low to High transition for address modification.	7_	
26	TEST	Test input Used in conjunction with four NEXT ADDRESS CONTROL FUNCTION commands to effect conditional skips, branches, and stack operations.	Active high	
7	GND	Ground		
22	vcc	+5 Volt supply		

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FUNCTIONAL DESCRIPTION

The Signetics 8X02 Control Store Sequencer is an LSI device using low power Schottky technology and is intended for use in high performance microprogrammed applications. When used alone, the 8X02 is capable of addressing up to 1K words of microprogram. This may be expanded to any microprogram size by conventional paging techniques.

The Address Register consists of 10 D-type, edge-triggered flip-flops with a common clock. A new address is entered into the Address Register on the low-to-high transition of the clock. The next address to be entered into the Address Register is supplied via the Address Multiplexer.

The Address Multiplexer is a 5-input device that is used to select either the branch input, +1 adder, +2 adder, stack register file, or ground (all zeros) as the source of the next microinstruction address. The proper multiplexer channel is automatically selected via the Decode Logic according to the Address Control Function Input and Test Input line.

The +1, +2 logic is used to increment the present contents of the Address Register by 1 or 2, depending on the function input command. Thus, the next address to the Control Store ROM/PROM may be either the current address plus 1 (N+1) or the current address plus 2 (N+2). If the same Microprogram Address is to be used on successive occasions, the clock to the 8X02 must simply be disabled; therefore, no new address is loaded into the Address Register.

The Stack File Register is used to provide a return address linkage whenever a subroutine or loop is executed. The 4X10 stack operates in a last-in, first-out (LIFO) mode, with the stack pointer always pointing to the next address to be read. Operation of the stack pointer is automatically controlled by the Address Control Function Inputs. Since the stack is 4 words deep, up to 4 loops and/or subroutines may be nested.

The branch input is a 10-bit field of direct inputs to the multiplexer which can be selected as the next control store address. Using the appropriate branch command, an N-way branch is possible where N is the

address of any microinstruction within the 1024 word microcode page. Likewise, the RESET command is a special case of an N-way branch in which the multiplexer selects an all zeros input, forcing the next microinstruction address to be zero.

The Test Input line is used in conjunction with the conditional execution of 4 Address Control Function commands. When the Test Input is false (low), the sequencer simply increments to the next address (N+1). When it is true (high), the sequencer executes a branch as defined by the input command, thereby transferring control to another portion of the microprogram.

All Address Output lines of the 8X02 are three-state buffered outputs with a common enable line $(\overline{\text{EN}})$. When the Enable line is high, all outputs are placed in a high-impedance state, and external access to the control store ROM/PROM is possible. This allows a preprogrammed set of microinstructions to be executed from external or built-in test equipment (BITE), vectored interrupts, and Writable Control Store if implemented.

NEXT ADDRESS CONTROL FUNCTION TABLE

MNEMONIC	DESCRIPTION	FUNC AC ₂			TEST	NEXT ADDRESS	STACK	STACK POINTER	
TSK	Test and skip		0		False True	Current + 1 Current + 2	N.C.	N.C. N.C.	
INC	Increment	0	0	1	×	Current + 1	N.C.	N.C.	
BLT	Branch to loop if test input true	0	1	0	False True	Current + 1 Stack reg file	X POP (read)	Decr Decr	
POP	POP stack	0	1	1	×	Stack reg file	POP (read)	Decr	
BSR	Branch to sub- routine if test input true	1	0	0	False True	Current + 1 Branch address	N.C. PUSH (Curr + 1)	N.C. Incr	
PLP	Push for looping	1	0	1	x	Current + 1	PUSH (Curr Addr)	Incr	
BRT	Branch if test input true	1	1	0	False True	Current + 1 Branch address	N.C. N.C.	N.C. N.C.	
RST	Set microprogram address output to zero	1	1	1	X	All O's	N.C.	N.C.	

X = Don't care
N.C. = No change

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FUNCTIONAL DESCRIPTION

The following is a description of each of the eight Next Address Control Functions (AC $_2$ -AC $_0$)

MNEMONIC	FUNCTION DESCRIPTION
TSK	AC ₂₋₀ = 000: TEST AND SKIP Perform test on Test Input Line. If test is Next Address = Current Address + 1 False (Low): Stack Pointer unchanged If test is Next Address = Current Address + 2 True (High) (i.e. Skip next microinstruction) Stack Pointer unchanged
INC	AC ₂₋₀ = 001: INCREMENT Next Address = Current Address + 1 Stack Pointer unchanged
BLT	AC ₂₋₀ = -010: BRANCH TO LOOP IF TEST CONDITION TRUE. Perform test on Test Input Line. If test is Next Address = Current Address + 1 False (Low): Stack Pointer decremented by 1 If test is Next Address = Address from Stack True (High): Register File (POP) Stack Pointer decremented by 1
POP	AC ₂₋₀ = 011: POP STACK Next Address = Address from Stack Register File (POP) Stack Pointer decremented by 1
BSR	AC ₂₋₀ = 100: BRANCHTO SUBROUTINE IF TEST CONDITION TRUE. Perform test on Test Input Line. If test is Next Address = Current Address + 1 False (Low): Stack Pointer unchanged If test is Next Address = Branch Address Input (B ₀₋₉) True (High): Stack Pointer incremented by 1 PUSH (write) Current Address + 1 - Stack Register File
PLP	AC ₂₋₀ = 101: PUSH FOR LOOPING Next Address = Current Address + 1 Stack Pointer incremented by 1 PUSH (write) Current Address → Stack Register File
BRT	AC _{2.0} = 110: BRANCH ON TEST CONDITION TRUE Perform test on Test Input Line. If test is Next Address = Current Address + 1 False (Low): Stack Pointer unchanged If test is Next Address = Branch Address Input (B _{0.9}) True (High): Stack Pointer unchanged
RST	AC ₂₋₀ = 111: RESET TO ZERO Next Address = 0 Stack Pointer unchanged

ABSOLUTE MAXIMUM RATINGS

	PARAMETER	RATING	UNIT
VCC	Power supply voltage	+7	Vdc
VIN	Input voltage	+5.5	Vdc
VO	Off-State output voltage	+5.5	Vdc
TA	Operating temperature range	0° to +70°	°C
TSTG	Storage temperature range	-65° to +150°	°C

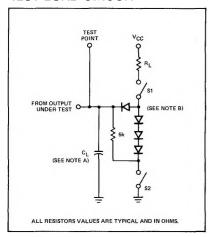
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DC ELECTRICAL CHARACTERISTICS TA = 0° C to +70°C, 4.75 \leq V $\overline{CC} \leq$ 5.25V

	PARAMETER	TEST CONDITIONS		LIMITS		UNIT
	PARAMETER	TEST CONDITIONS	Min	Typ1	Max	ONIT
VIH	High level input voltage		2			V
V ₁ L	Low level input voltage				0.8	V
V,	Input clamp voltage	V _{CC} = 4.75V, I _I = -18mA		ļ	-1.5	V
V _{OH}	High level output voltage	V _{CC} = 4.75V, I _{OH} = -2.6mA	2.4			V
VOL	Low level output voltage	V _{CC} = 4.75V, I _{OL} = 8mA			0.5	V
11	Input current at maximum Input voltage	V _{CC} = 5.25V, V _I = 5.5V			100	μΑ
ЧН	High level input current AC_2 - AC_0 , \overline{EN} , TEST B_9 - B_0 CLK	V _{CC} = 5.25V, V _I = 2.7V			40 20 60	μΑ μΑ μΑ
IL	Low level input current AC_2 - AC_0 , \overline{EN} , TEST B_9 - B_0 CLK	V _{CC} = 5.25V, V _I = 0.4V			-0.72 -0.36 -1.08	mA mA mA
los	Short-circuit output current	V _{CC} = 5.25V	-15	ĺ	-100	mA
l 'ozh	High-Z state output current	V _{OUT} = 2.7V		}	20	μΑ
OZL	High-Z state output current	V _{OUT} = 0.4V			-20	μA
¹cc	Supply current	V _{CC} = 5.25V		165	200	mA

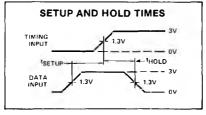
NOTE

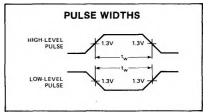
TEST LOAD CIRCUIT

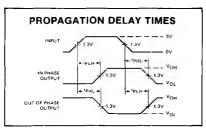


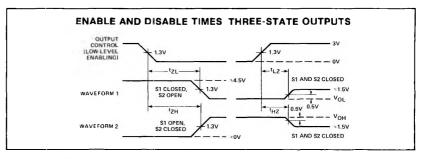
- A. C_L includes probe and jig capacitance.
 B. All diodes are 1N916 or 1N3064.
- C. RL = 2k, C = 15pF.

VOLTAGE WAVEFORMS









^{1.} All typical values are at $V_{\overline{CC}}$ = 5V, $T_{\overline{A}}$ = 25°C.

CONTROL STORE SEQUENCER

PRELIMINARY SPECIFICATION

8X02-I,XL

AC ELECTRICAL CHARACTERISTICS $T_A \approx 0^{\circ}$ -70°C, $V_{CC} = 5.0V \pm 5\%$

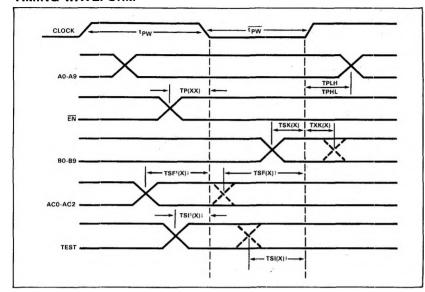
	PARAMETER	то	FROM		UNIT		
	PANAMETER	'	PROMI	Min	Typ1	Max	
^t HI ⁽¹⁾ (0)	Test			0 0	-10 -24		ns
^t SF ¹ (1) (0)	Control and data input setup times with respect to CLK (1) for stack related functions (BLT, POP, BSR, PLP) (2) AC ₀ -AC ₂			35 35	23 22		ns
t _{SI} 1 (1) (0)	Test		!	28 28	23 22		
tPLZ tPHZ tPZL tPZH	Propagation delay Low to high Z High to high Z High to low High Z to high Propagation delay	A ₀ -A ₉	EN Clock		12 16 14 15	35 35 25 35	ns
^t PHL ^t PLH	High to low Low to high				33 33	40 40	
t PW	Clock pulse width High Low			50 60	36 42		ns
^t SF (1) (0) ^t SK (1) (0) ^t SI (1) (0)	Control and data input setup times with respect to CLK (1) for non-stack related functions (TSK, INC, BRT, RST) AC ₀ -AC ₂ B ₀ -B ₉ ² Test			90 90 27 29 60	70 70 22 24 45 45	0	ns
^t HF (1) (0) ^t HK (1) (0)	Control and data input hold times with respect to CLK (1) AC ₀ -AC ₂ B ₀ -B ₉ ²			0 0 0	-7 -12 -12 -10		ns

NOTES

^{1.} Typical values are to T $_A$ = 25°C and V $_{CC}$ = 5.0 volts 2. $B_0\text{-}B_9$ inputs are required to Clock (1) only. See TSK (1) and TSK (0).

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TIMING WAVEFORM



PULSE WIDTH (TPW) vs TEMPERATURE

